

Notice of References Cited

Application/Control No.

10/630,886

Applicant(s)/Patent Under
Reexamination
ALEXANDER ET AL.

Examiner

Tuan T. Dinh

Art Unit

2841

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,652,562	07-1997	Riley, Richard E.	337/405
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Precision Resistor Networks, Resistors Advanced Information, Honeywell
	V	Configuring a Discrete Resistor Verification Test System, Keithly Instrument Inc.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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